

| | | | |
|-----------------------------------|---------------------------------------|--------------------------------------------------------------|-------------|
| Notice of References Cited | Application/Control No. 10/717,401 | Applicant(s)/Patent Under Reexamination HUEBNER ET AL. | |
| | Examiner D. Austin Bonderer | Art Unit 3732 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--------------------------------------------------|-----------------|-------------------|----------------|
| | A | US-5,429,641 A | 07-1995 | Gotfried, Yechiel | 606/67 |
| | B | US-5,458,654 A | 10-1995 | Tepic, Slobodan | 623/23.27 |
| | C | US-2002/0133172 A1 | 09-2002 | Lambrecht et al. | 606/130 |
| | D | US-2003/0083661 A1 | 05-2003 | Orbay et al. | 606/69 |
| | E | US-2004/0006349 A1 | 01-2004 | Goble et al. | 606/104 |
| | F | US-5,613,971 A | 03-1997 | Lower et al. | 606/96 |
| | G | US-6,129,730 A | 10-2000 | Bono et al. | 606/73 |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--------------------------------------------------|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|-------------------------------------------------------------------------------------------|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.